MFP-3D[™] Extended Head for High Feature Samples

Asylum Research

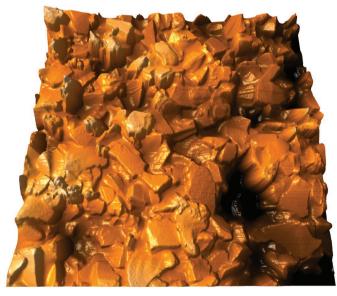
Introduction

As sample features increase in height, a larger Z-range is required. Asylum Research has developed the **MFP-3D Extended Head** for use in its **MFP-3D** Atomic Force Microscopy (AFM) Systems. The new head design allows a scan range of 40 µm in Z for samples with higher features, and in particular, for bioscience applications including living cells and plant imaging.

The MFP-3D Extended Head utilizes the same Nanopositioning System (NPS™) sensors found in the standard head for unprecedented precision and accuracy. Z sensor noise is <0.3 nm Adev in a 0.1 Hz-1 kHz bandwidth (BW) and sensor non-linearity less than 0.2% (Adev/full travel) at full scan; Z height noise <0.06 nm Adev, 0.1 Hz-1 kHz BW. The MFP-3D Extended Head is offered as an option in MFP-3D system configurations.



The 40 µm Z scan range Extended Head is ideal for imaging bioscience samples such as living cells, plant imaging, and pulling on long-chained molecules.



2500 Grit Sand Paper. This sample required 19 μm of Z range, 90 μm scan.



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